

N-Channel 700V (D-S) Power MOSFET

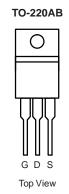
PRODUCT SUMMARY					
V _{DS} (V)	700				
R _{DS(on)} max. at 25 °C (Ω)	V _{GS} = 10 V 0.97				
Q _g max. (nC)	40				
Q _{gs} (nC)	4				
Q _{gd} (nC)	20				
Configuration	Single				

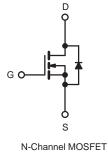
FEATURES

- Low figure-of-merit (FOM) Ron x Qa
- Low input capacitance (Ciss)
- Reduced switching and conduction losses
- Ultra low gate charge (Qg)
- Avalanche energy rated (UIS)

APPLICATIONS

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
 - High-intensity discharge (HID)
 - Fluorescent ballast lighting
- Industrial





ABSOLUTE MAXIMUM RATINGS (T _C	= 25 °C, unl	ess otherwis	se noted)			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage		V _{DS}	700	V		
Gate-Source Voltage			V _{GS}	± 30	v	
Continuous Drain Current (T, = 150 °C)	V _{GS} at 10 V	$T_{\rm C} = 25 \ ^{\circ}{\rm C}$ $T_{\rm C} = 100 \ ^{\circ}{\rm C}$	la.	10		
Continuous Drain Current (1) = 150°C)	VGS at TO V	T _C = 100 °C	I _D	8.4	A	
Pulsed Drain Current ^a			I _{DM}	36		
Linear Derating Factor				3.6	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	280	mJ	
Maximum Power Dissipation			PD	97	W	
Operating Junction and Storage Temperature Range	e		T _J , T _{stg}	-55 to +150	°C	
ain-Source Voltage Slope $T_J = 125 \text{ °C}$ dV/dt 15		V/ns				
Reverse Diode dV/dt ^d		uv/di	4.1	v/ns		
Soldering Recommendations (Peak Temperature) ^c	for	10 s		300	°C	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature. b. $V_{DD} = 50$ V, starting T_J = 25 °C, L = 28.2 mH, R_g = 25 Ω , I_{AS} = 4.5 A.

c. 1.6 mm from case.

d. $I_{SD} \leq I_D$, dI/dt = 100 A/µs, starting T_J = 25 °C.





THERMAL RESISTANCE RATI	NGS							
PARAMETER	SYMBOL	TYP.		MAX.			UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-		60	60			
Maximum Junction-to-Case (Drain)	R _{thJC}	-		0.8			°C/W	
SPECIFICATIONS (T _J = 25 °C, u	nless otherwi	se noted)						
PARAMETER	SYMBOL	TES	T CONDIT	IONS	MIN.	TYP.	MAX.	UNIT
Static					•			-
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} =	= 0 V, I _D =	250 µA	700	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C,	I _D = 1 mA	-	0.75	-	V/°C
Gate-Source Threshold Voltage (N)	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D =	250 µA	2	-	4	V
		V _{GS} = ± 20 V		-	-	± 100	nA	
Gate-Source Leakage	I _{GSS}	,	V _{GS} = ± 30	V	-	-	± 1	μA
		$V_{DS} = 700 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$ $V_{DS} = 560 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 125 \text{ °C}$		_{as} = 0 V	-	-	1	μA
Zero Gate Voltage Drain Current	IDSS			V, T _J = 125 °C	-	-	10	
Drain-Source On-State Resistance	R _{DS(on)}	$V_{GS} = 10 V$		I _D = 8 A	-	0.97	-	Ω
Forward Transconductance	g fs	V _{DS}	= 30 V, I _D	= 8 A	-	16	-	S
Dynamic					•	•	•	
Input Capacitance	C _{iss}		$V_{GS} = 0 V$	/	-	850	-	
Output Capacitance	C _{oss}	V _{DS} = 100 V, - 80 f = 1 MHz - 10			-	80	-	
Reverse Transfer Capacitance	C _{rss}				-			
Effective Output Capacitance, Energy Related ^a	C _{o(er)}	V – 0)		V – 0.V	-	63	-	pF
Effective Output Capacitance, Time Related ^b	C _{o(tr)}	$V_{DS} = 0 V$ to 560 V, $V_{GS} = 0 V$		-	213	-		
Total Gate Charge	Qg			-	43	-		
Gate-Source Charge	Q _{gs}	$V_{GS} = 10 V$	I _D = 8 /	A, V _{DS} = 560 V	-	5	-	nC
Gate-Drain Charge	Q _{gd}				-	22	-	
Turn-On Delay Time	t _{d(on)}				-	13	25	
Rise Time	t _r	V _{DD}	= 560 V, I _D	o = 8 A,	-	11	35	ns
Turn-Off Delay Time	t _{d(off)}	$V_{GS} = 10 \text{ V}, \text{ R}_{g} = 9.1 \Omega$		-	81	90	-	
Fall Time	t _f				-	25	40	~
Gate Input Resistance	Rg	f = 1	MHz, ope	n drain	-	3.5	-	Ω
Drain-Source Body Diode Characteristic	s					1	1	
Continuous Source-Drain Diode Current	I _S	MOSFET syml showing the	loc		-	-	15	^
Pulsed Diode Forward Current	I _{SM}	p - n junction diode		-	40	A		
Diode Forward Voltage	V _{SD}	T _J = 25 °C, I _S = 8 A, V _{GS} = 0 V		-	-	1.5	V	
Reverse Recovery Time	t _{rr}			-	-	345	-	ns
Reverse Recovery Charge	Q _{rr}		5 °C, I _F =		-	4.5	-	μC
Reverse Recovery Current	I _{RRM}	ai/at = 1	ου Α/μs, \	/ _R = 400 V	-	35	_	A

Notes

a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

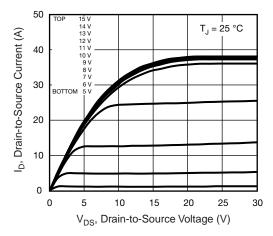


Fig. 1 - Typical Output Characteristics

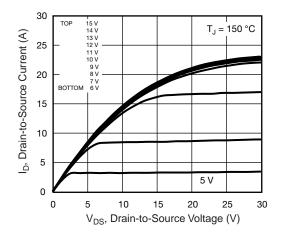


Fig. 2 - Typical Output Characteristics

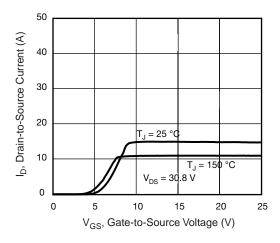


Fig. 3 - Typical Transfer Characteristics

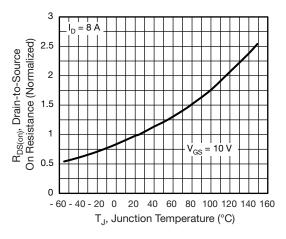


Fig. 4 - Normalized On-Resistance vs. Temperature

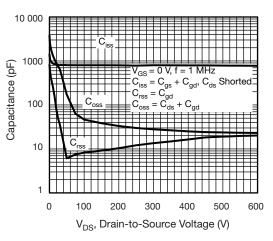


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

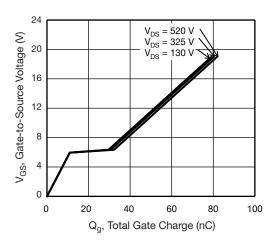


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

VBM17R10



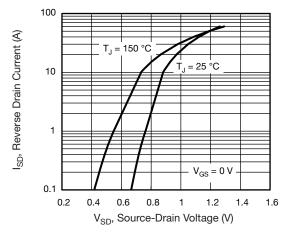


Fig. 7 - Typical Source-Drain Diode Forward Voltage

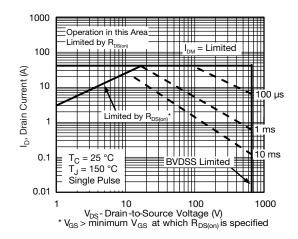


Fig. 8 - Maximum Safe Operating Area

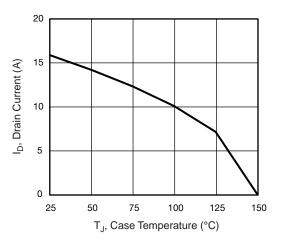


Fig. 9 - Maximum Drain Current vs. Case Temperature

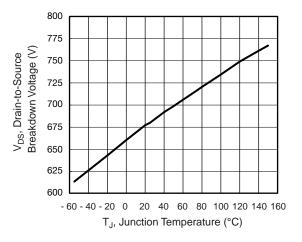


Fig. 10 - Temperature vs. Drain-to-Source Voltage

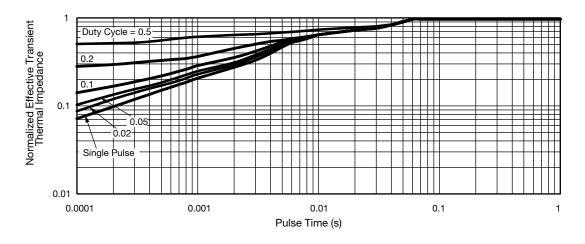


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



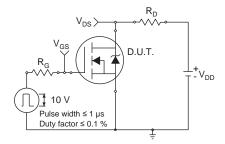


Fig. 12 - Switching Time Test Circuit

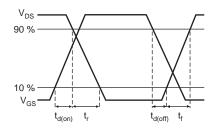


Fig. 13 - Switching Time Waveforms

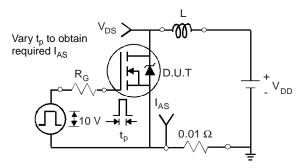


Fig. 14 - Unclamped Inductive Test Circuit

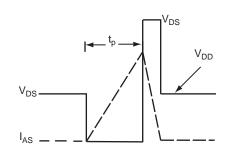


Fig. 15 - Unclamped Inductive Waveforms

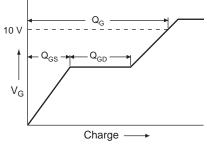


Fig. 16 - Basic Gate Charge Waveform

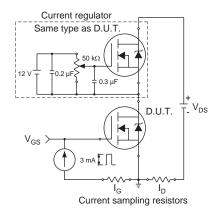
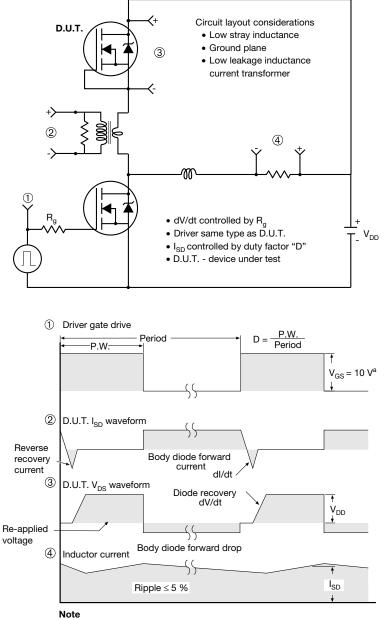


Fig. 17 - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

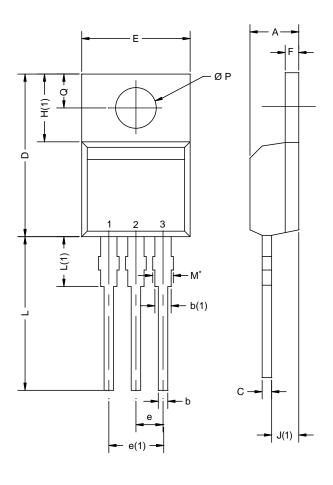


a. $V_{GS} = 5$ V for logic level devices

Fig. 18 - For N-Channel



TO-220AB



	MILLIN	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØР	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12- DWG: 547	0208-Rev. N, 1	08-Oct-12			

Notes

* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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